

## WEST Search History





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	<i>DB=USPT,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>		
<input type="checkbox"/>	L17	L16 same (fail\$4 or fault or error)	14
<input type="checkbox"/>	L16	(adjust\$4 near5 event near5 (respons\$4 or notif\$9))	178
<input type="checkbox"/>	L15	L14 same policy	15
<input type="checkbox"/>	L14	fault with event with (notif\$9 or respon\$7)	812
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<input type="checkbox"/>	L12	(event adj policy)	64
<input type="checkbox"/>	L11	(event near2 policy)	217
<input type="checkbox"/>	L10	(default near5 (event near2 policy))	0
<input type="checkbox"/>	L9	(default near2 event near2 policy)	0
<input type="checkbox"/>	L8	L3 and (default with response with event)	2
<input type="checkbox"/>	L7	L3 and default	61
<input type="checkbox"/>	L6	l3.clm.	43
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<input type="checkbox"/>	L1	(event with respon\$4) same default same (modif\$9 or configur\$4 or chang\$4 or alter\$4 or switch\$4)	165

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